Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/665,698	XUE, XIN
Examiner	Art Unit
Alan S. Chen	2182

SEARCHED							
Class	Subclass	Date		Examiner			
710	52	6/2/2006		6/2/2006 AS		sc	
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709	217-219						
707	200						

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT Inventor Search	6/2/2006	ASC
NPL search IP.com IEEE Xplore	6/2/2006	ASC